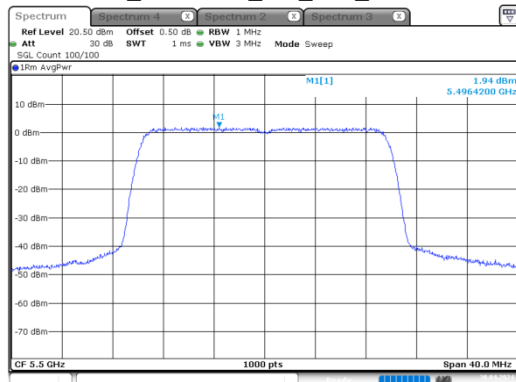
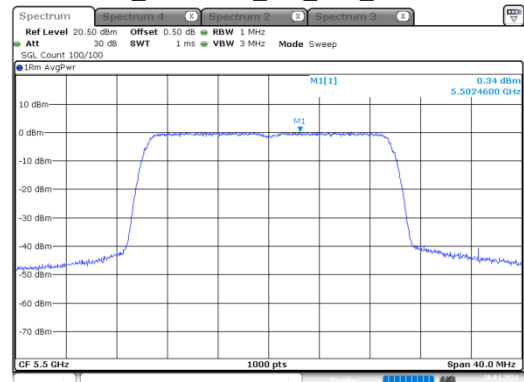


ax20_5500MHz_RU_Full_Chain 0



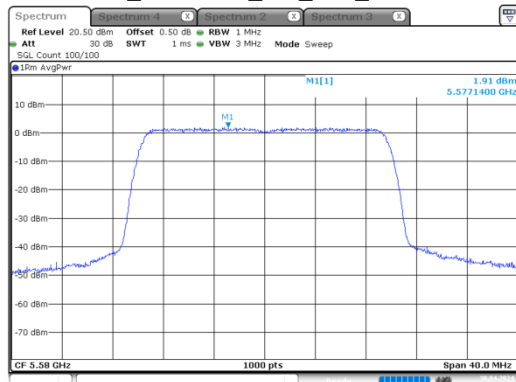
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:29:45

ax20_5500MHz_RU_Full_Chain 1



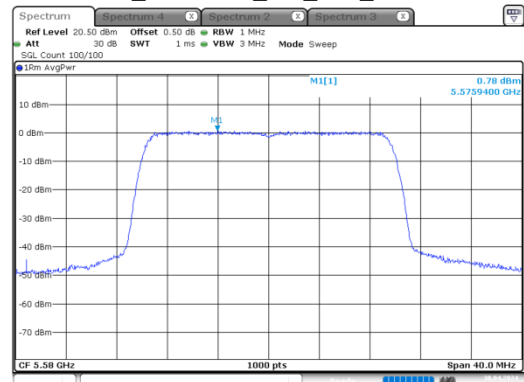
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:44:44

ax20_5580MHz_RU_Full_Chain 0



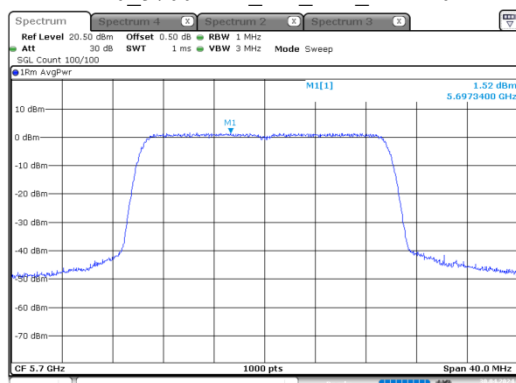
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:30:59

ax20_5580MHz_RU_Full_Chain 1



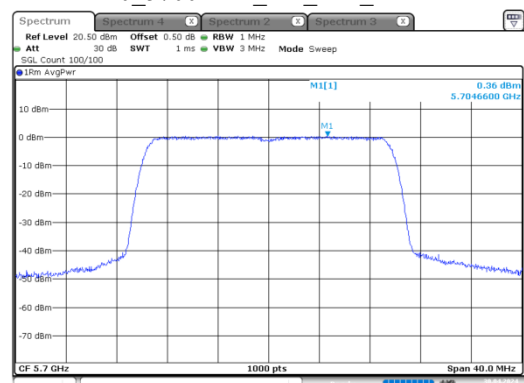
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:48:48

ax20_5700MHz_RU_Full_Chain 0



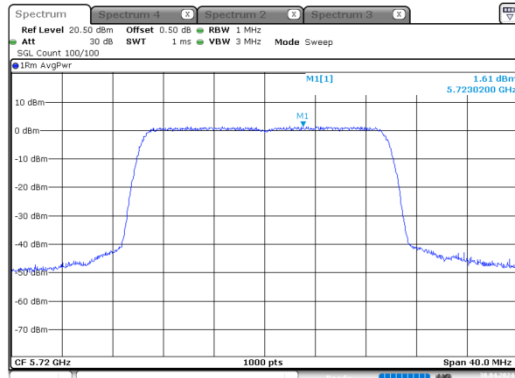
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:32:56

ax20_5700MHz_RU_Full_Chain 1



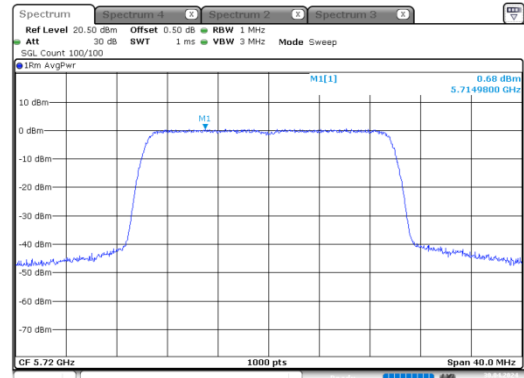
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:49:28

ax20_5720MHz_RU_Full_Chain 0



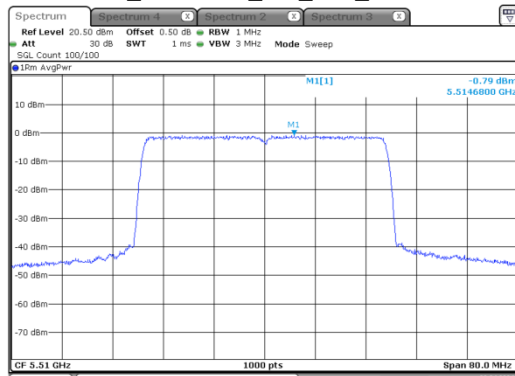
ProjectNo.:2402S71481E-RF Tester: Alice Tan
Date: 30.APR.2024 19:33:50

ax20_5720MHz_RU_Full_Chain 1



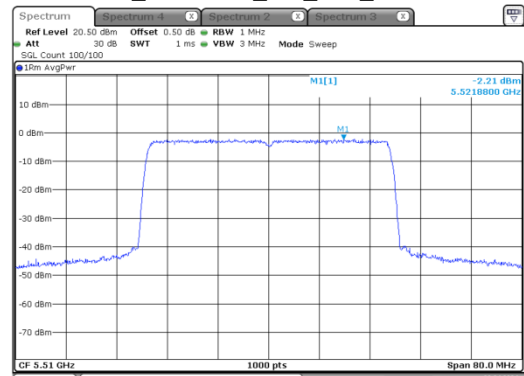
ProjectNo.:2402S71481E-RF Tester: Alice Tan
Date: 30.APR.2024 19:50:07

ax40_5510MHz_RU_Full_Chain 0



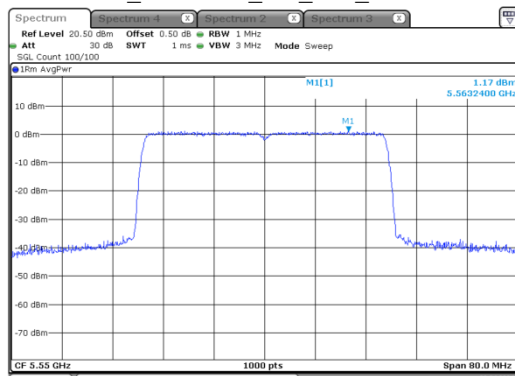
ProjectNo.:2402S71481E-RF Tester: Alice Tan
Date: 30.APR.2024 19:34:53

ax40_5510MHz_RU_Full_Chain 1



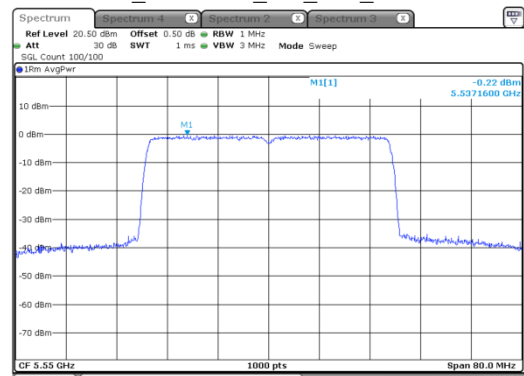
ProjectNo.:2402S71481E-RF Tester: Alice Tan
Date: 30.APR.2024 19:51:36

ax40_5550MHz_RU_Full_Chain 0



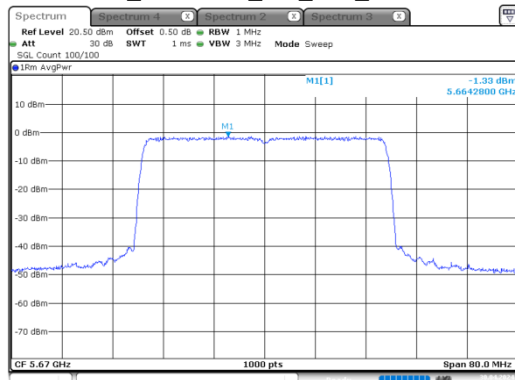
ProjectNo.:2402S71481E-RF Tester: Alice Tan
Date: 30.APR.2024 19:35:55

ax40_5550MHz_RU_Full_Chain 1



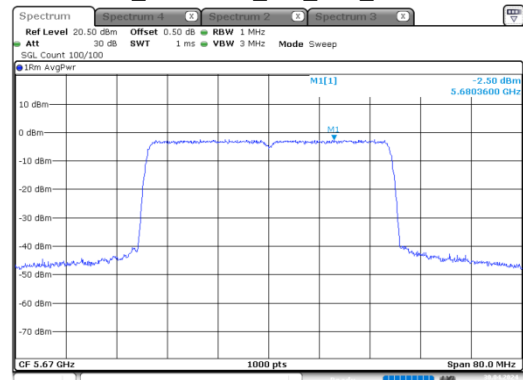
ProjectNo.:2402S71481E-RF Tester: Alice Tan
Date: 30.APR.2024 19:52:14

ax40_5670MHz_RU_Full_Chain 0



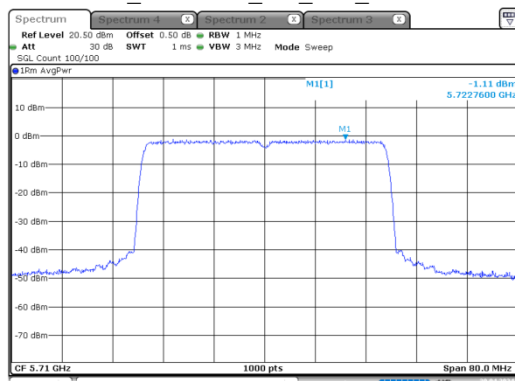
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:16:55

ax40_5670MHz_RU_Full_Chain 1



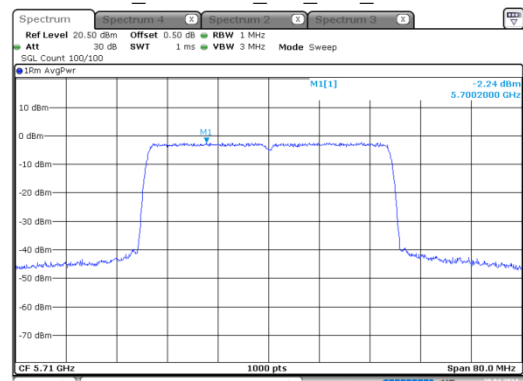
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:15:48

ax40_5710MHz_RU_Full_Chain 0



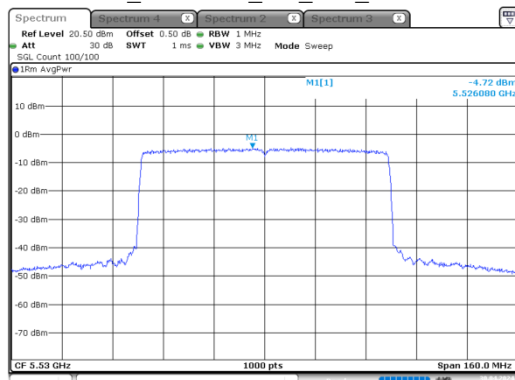
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:17:55

ax40_5710MHz_RU_Full_Chain 1



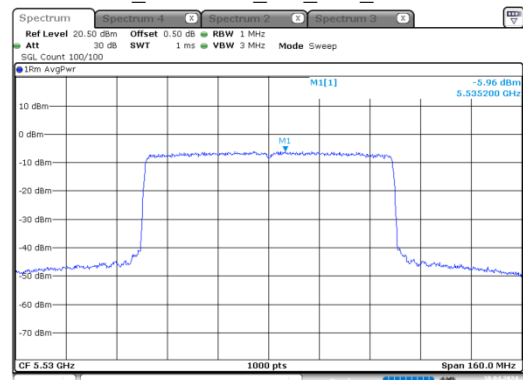
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:15:22

ax80_5530MHz_RU_Full_Chain 0



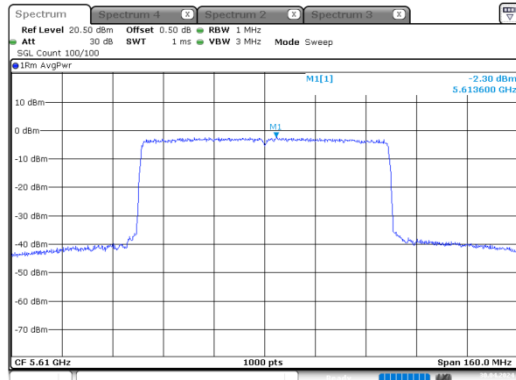
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:19:09

ax80_5530MHz_RU_Full_Chain 1



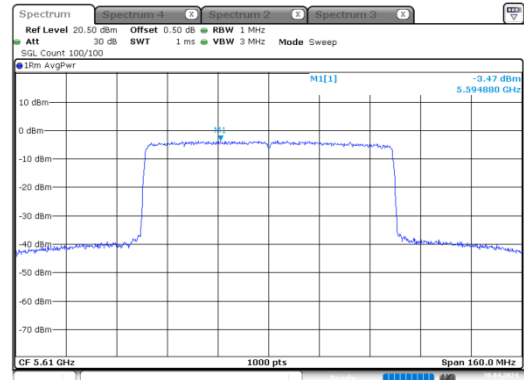
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:15:03

ax80_5610MHz_RU_Full_Chain 0



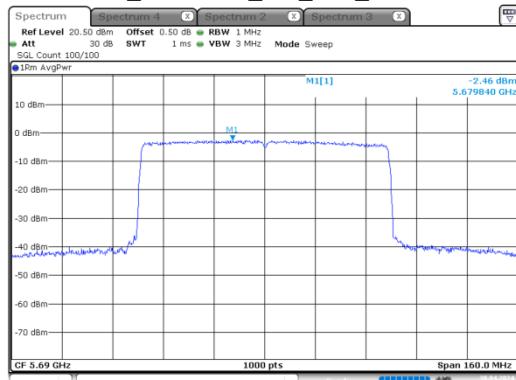
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:40:15

ax80_5610MHz_RU_Full_Chain 1



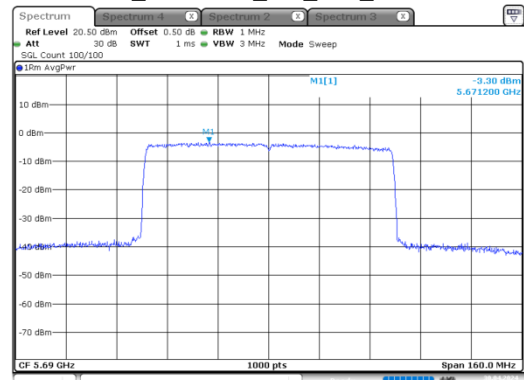
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:54:41

ax80_5690MHz_RU_Full_Chain 0



ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:41:18

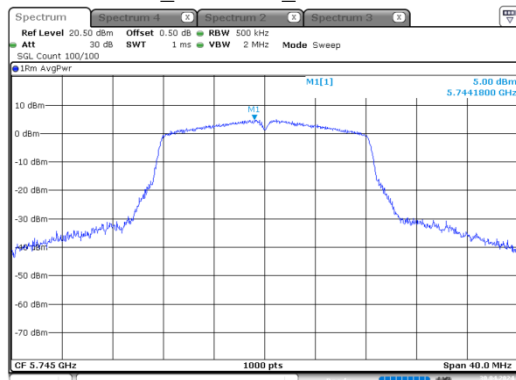
ax80_5690MHz_RU_Full_Chain 1



ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:55:20

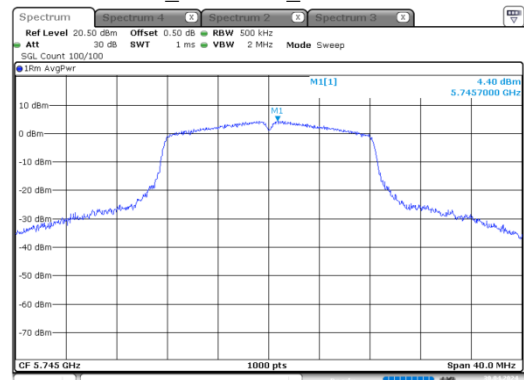
5725-5850MHz

a_5745MHz_Chain 0



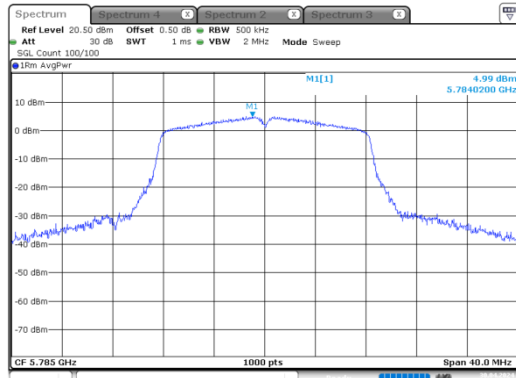
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:06:14

a_5745MHz_Chain 1



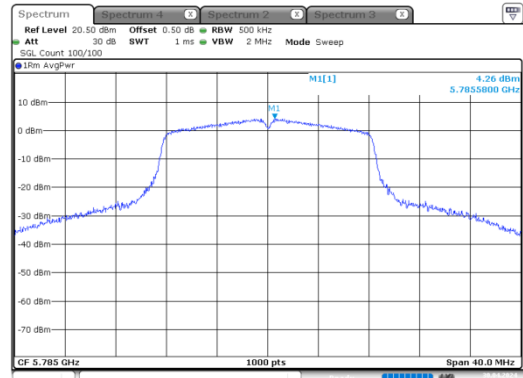
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 20:17:51

a_5785MHz_Chain 0



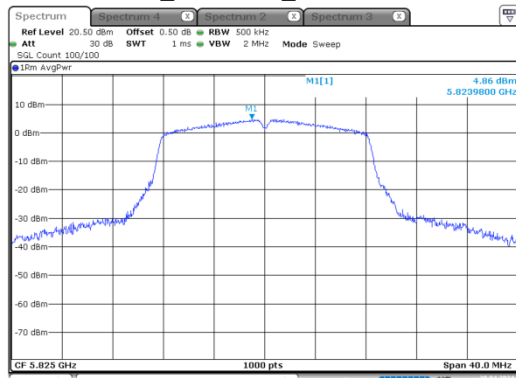
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:07:18

a_5785MHz_Chain 1



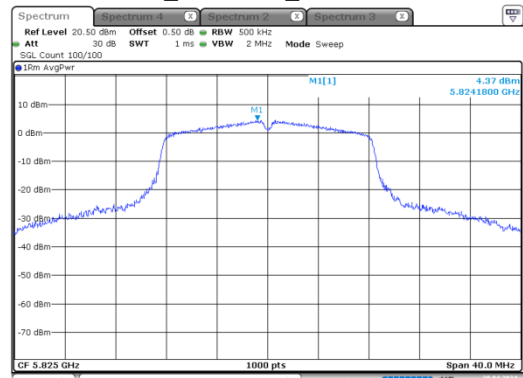
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 20:18:26

a_5825MHz_Chain 0



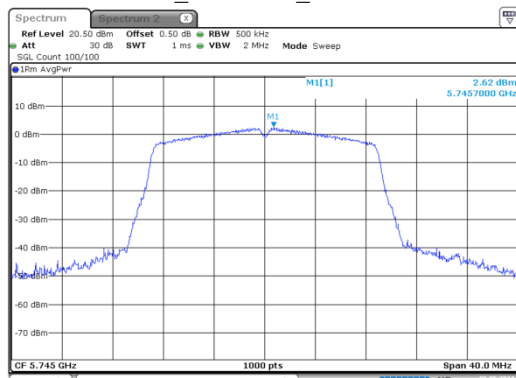
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:08:18

a_5825MHz_Chain 1



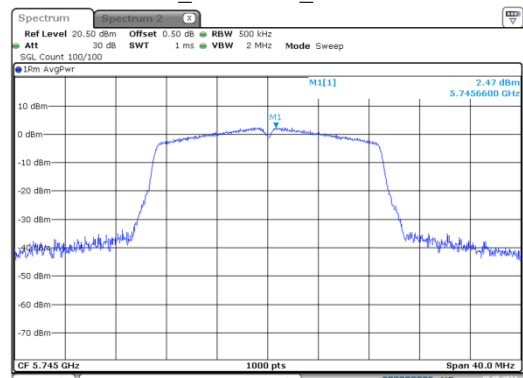
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 20:18:59

n20_5745MHz_Chain 0



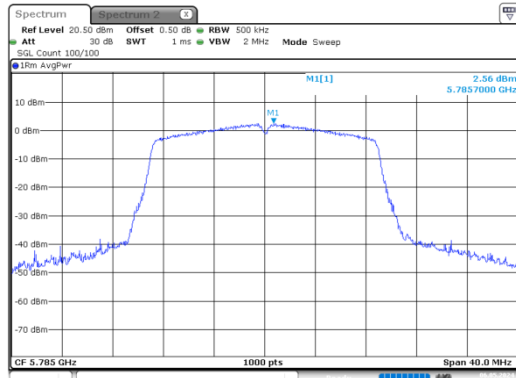
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 6.MAY.2024 14:28:30

n20_5745MHz_Chain 1



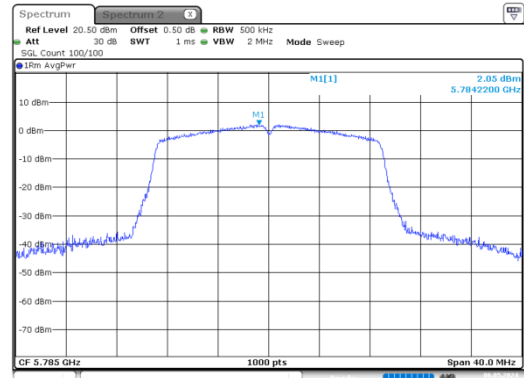
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 6.MAY.2024 14:33:07

n20_5785MHz_Chain 0



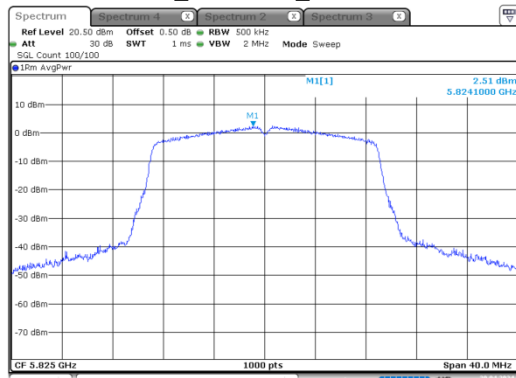
ProjectNo.:2402S71481E-RF Tester: Alice Tan
Date: 6.MAY.2024 14:29:39

n20_5785MHz_Chain 1



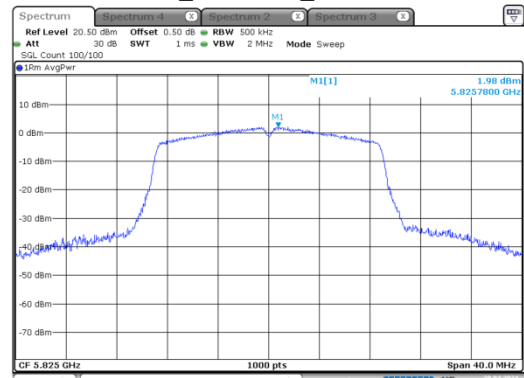
ProjectNo.:2402S71481E-RF Tester: Alice Tan
Date: 6.MAY.2024 14:33:54

n20_5825MHz_Chain 0



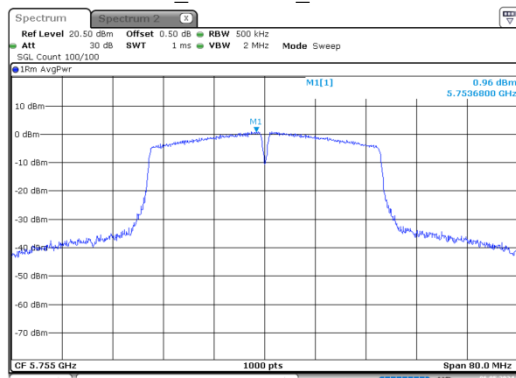
ProjectNo.:2402S71481E-RF Tester: Alice Tan
Date: 30.APR.2024 19:12:16

n20_5825MHz_Chain 1



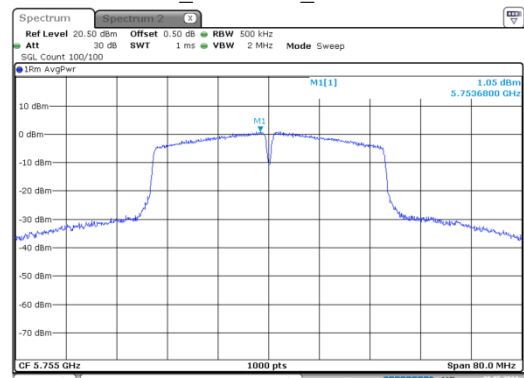
ProjectNo.:2402S71481E-RF Tester: Alice Tan
Date: 30.APR.2024 20:23:16

n40_5755MHz_Chain 0



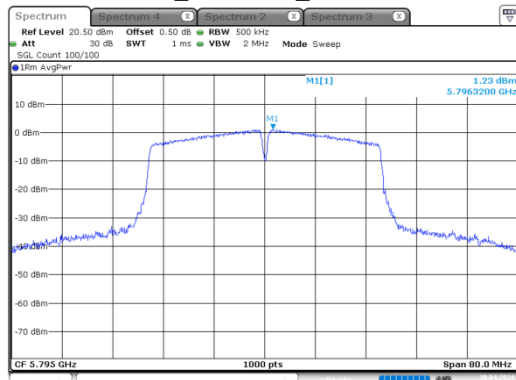
ProjectNo.:2402S71481E-RF Tester: Alice Tan
Date: 6.MAY.2024 14:30:52

n40_5755MHz_Chain 1



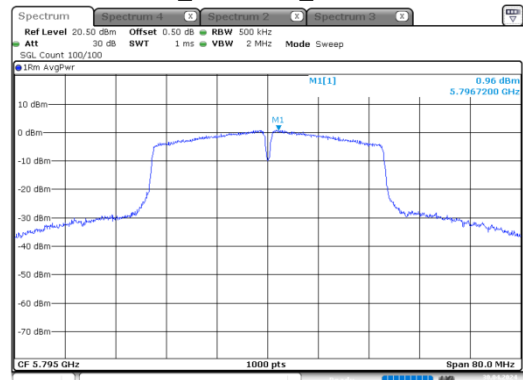
ProjectNo.:2402S71481E-RF Tester: Alice Tan
Date: 6.MAY.2024 14:32:12

n40_5795MHz_Chain 0



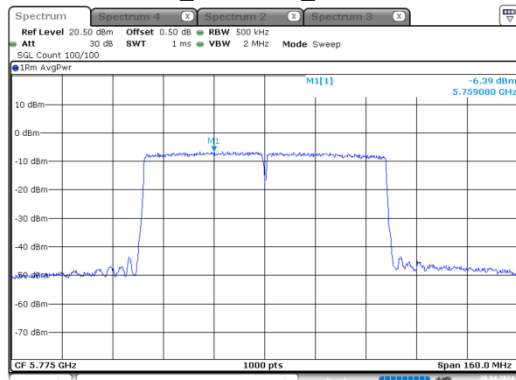
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:14:22

n40_5795MHz_Chain 1



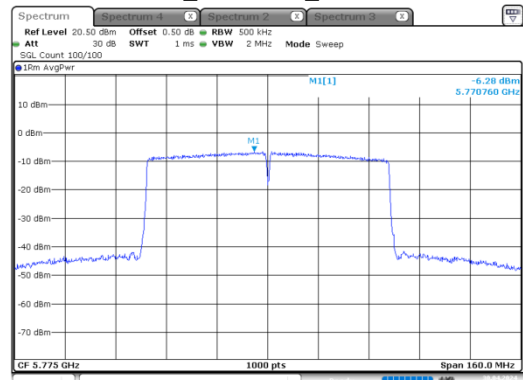
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 20:27:07

ac80_5775MHz_Chain 0



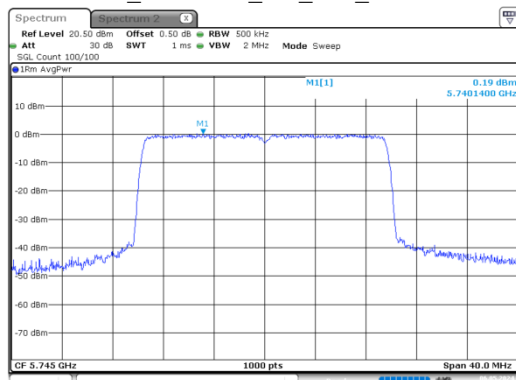
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:15:19

ac80_5775MHz_Chain 1



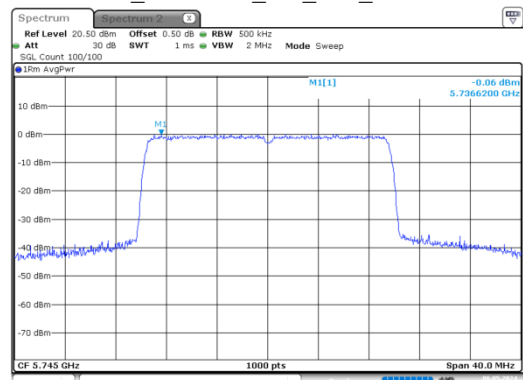
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 20:26:04

ax20_5745MHz_RU_Full_Chain 0



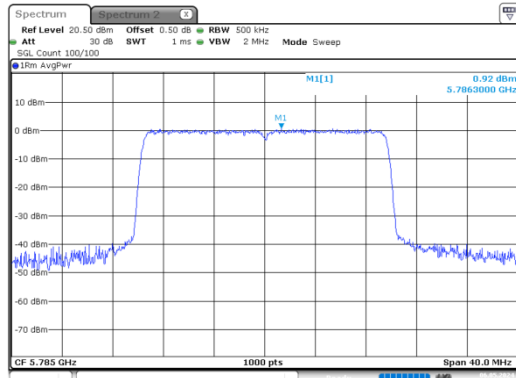
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 6.MAY.2024 14:37:11

ax20_5745MHz_RU_Full_Chain 1



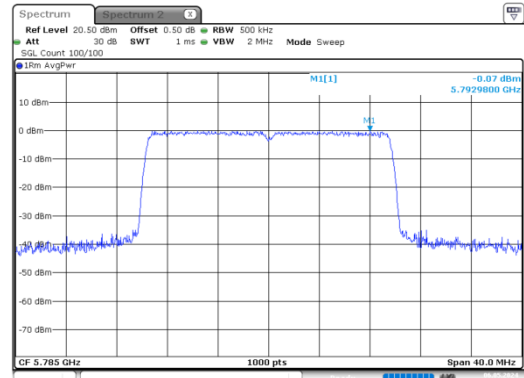
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 6.MAY.2024 14:40:00

ax20_5785MHz_RU_Full_Chain 0



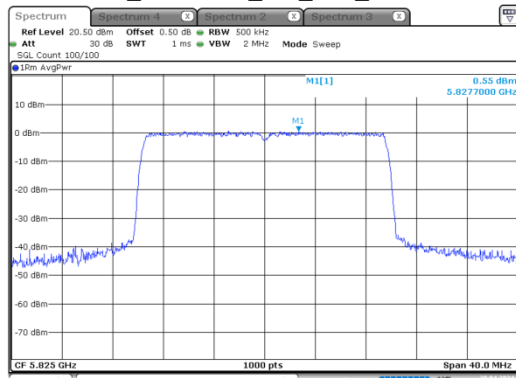
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 6.MAY.2024 14:37:49

ax20_5785MHz_RU_Full_Chain 1



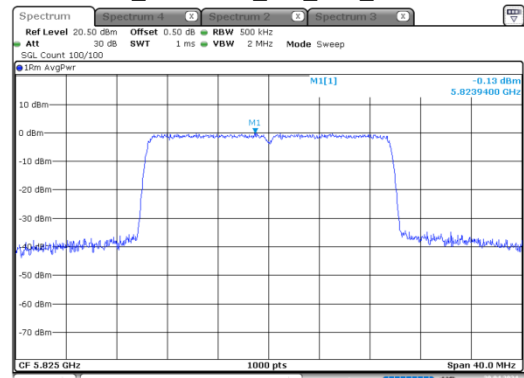
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 6.MAY.2024 14:40:37

ax20_5825MHz_RU_Full_Chain 0



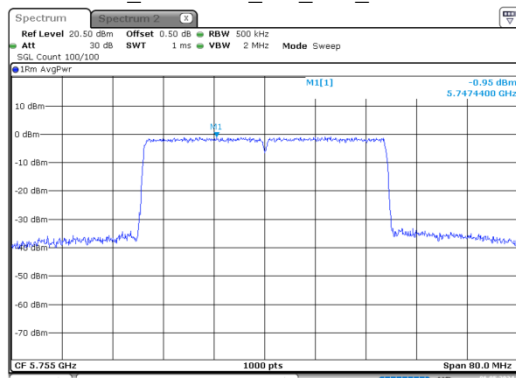
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:20:19

ax20_5825MHz_RU_Full_Chain 1



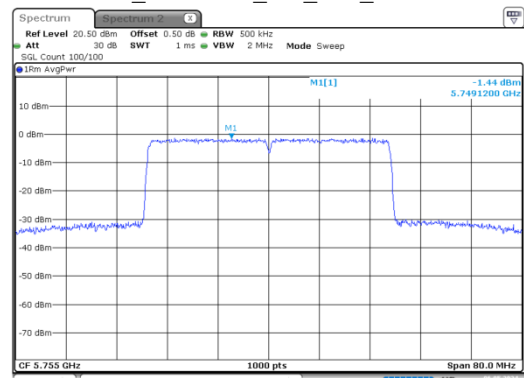
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 20:30:19

ax40_5755MHz_RU_Full_Chain 0



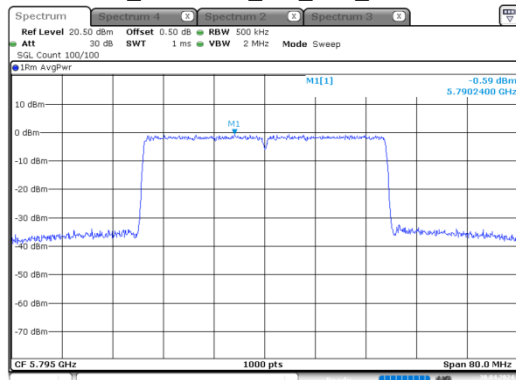
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 6.MAY.2024 14:38:38

ax40_5755MHz_RU_Full_Chain 1



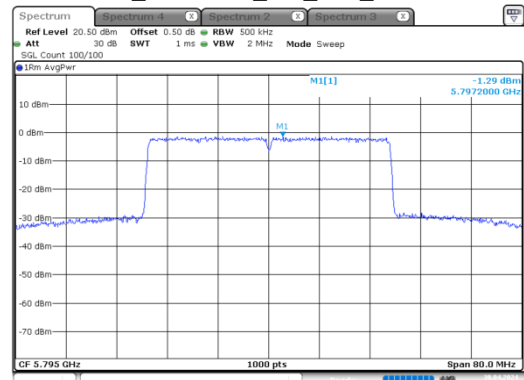
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 6.MAY.2024 14:41:18

ax40_5795MHz_RU_Full_Chain 0



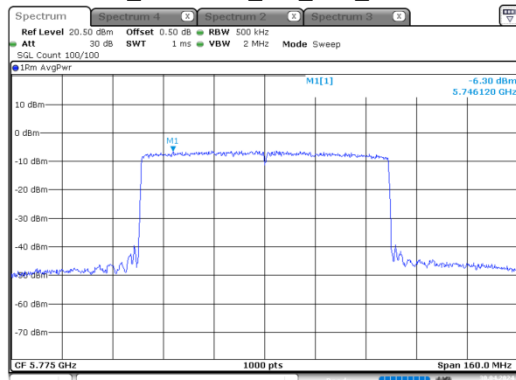
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:25:25

ax40_5795MHz_RU_Full_Chain 1



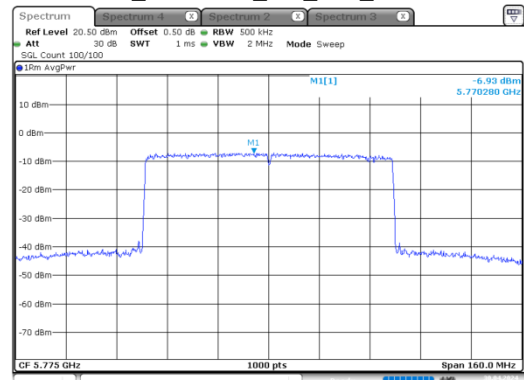
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 20:32:16

ax80_5775MHz_RU_Full_Chain 0



ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 19:26:46

ax80_5775MHz_RU_Full_Chain 1



ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 20:33:06

5.7 Duty Cycle

Serial No.:	OSEB119574-2	Test Date:	2024/04/30
Test Site:	RF	Test Mode:	Transmitting
Tester:	Alice Tan	Test Result:	/

Environmental Conditions:

Temperature: (°C)	24.1	Relative Humidity: (%)	63	ATM Pressure: (kPa)	100.5
-----------------------------	------	----------------------------------	----	-------------------------------	-------

Test Equipment List and Details:

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
R&S	Spectrum Analyzer	FSP 38	100478	2023/10/18	2024/10/17

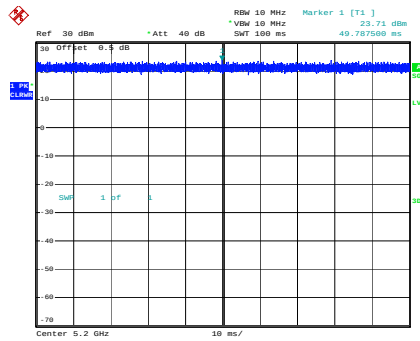
* Statement of Traceability: Bay Area Compliance Laboratories Corp. (Dongguan) attests that all calibrations have been performed, traceable to National Primary Standards and International System of Units (SI).

Test Data:**5150-5250MHz**

Mode	Ton (ms)	Ton+Toff (ms)	Duty Cycle (%)	Duty Cycle Factor (dB)	1/Ton (Hz)	VBW Setting (kHz)
a_5200MHz_Chain 0	100	100	100	0	/	0.01
n20_5200MHz_Chain 0	100	100	100	0	/	0.01
n40_5190MHz_Chain 0	100	100	100	0	/	0.01
ac80_5210MHz_Chain 0	100	100	100	0	/	0.01
ax20_5200MHz_RU_Full_Chain 0	100	100	100	0	/	0.01
ax40_5190MHz_RU_Full_Chain 0	100	100	100	0	/	0.01
ax80_5210MHz_RU_Full_Chain 0	100	100	100	0	/	0.01

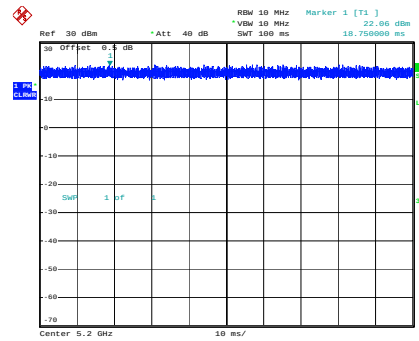
Duty Cycle = Ton/(Ton+Toff)*100%

a_5200MHz_Chain 0



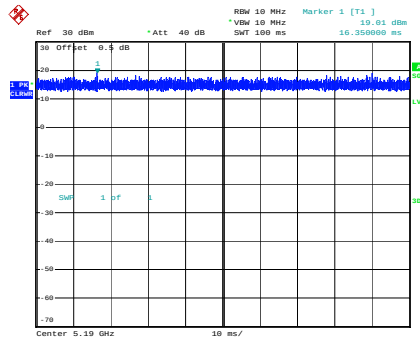
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 14:13:26

n20_5200MHz_Chain 0



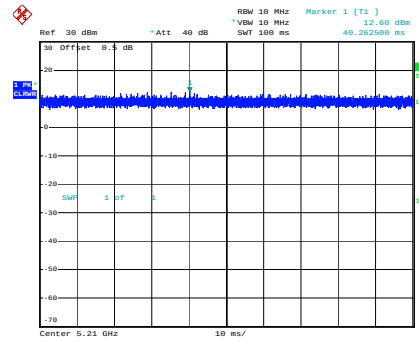
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 14:18:20

n40_5190MHz_Chain 0



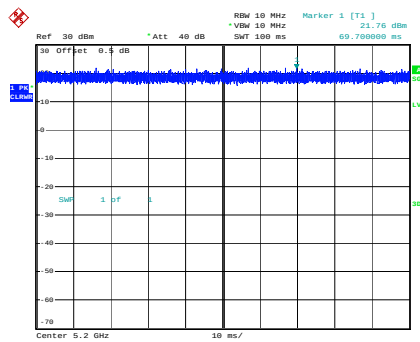
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 14:20:13

ac80_5210MHz_Chain 0



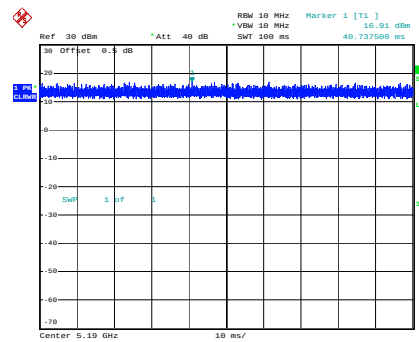
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 14:21:08

ax20_5200MHz_RU_Full_Chain 0



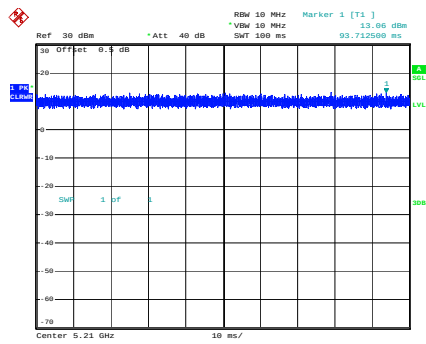
ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 17:25:30

ax40_5190MHz_RU_Full_Chain 0



ProjectNo.:2402S71481E-RF Tester:Alice Tan
Date: 30.APR.2024 17:26:06

ax80_5210MHz_RU_Full_Chain 0



ProjectNo.:2402S71481E-RF Tester:Alice Tan
 Date: 30.APR.2024 17:26:31

APPENDIX A - EUT PHOTOGRAPHS

Please refer to the attachment 2402S71481E-RF-EXP EUT EXTERNAL PHOTOGRAPHS and 2402S71481E-RF-INP EUT INTERNAL PHOTOGRAPHS.

APPENDIX B - TEST SETUP PHOTOGRAPHS

Please refer to the attachment 2402S71481E-RF-00D-TSP TEST SETUP PHOTOGRAPHS.

******* END OF REPORT *******